Application/Control No. Applicant(s)/Patent Under Reexamination 10/663,714 **INOUE ET AL** Notice of References Cited Art Unit Examiner Page 1 of 1 A. Sefer 2826 **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY US-6,462,354 10-2002 Okuyama, Hiroyuki 257/13 Α US-В US-С US-D US-Ε US-F US-G US-Н US-US-J US-Κ US-L US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν О Р Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W

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^{*}A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.